

Louis Giraudet

List of Publications by Year in descending order

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Version: 2024-02-01

11
papers

210
citations

1040056

9
h-index

1281871

11
g-index

11
all docs

11
docs citations

11
times ranked

498
citing authors

#	ARTICLE	IF	CITATIONS
1	Synthesis and characterization of 1,7-disubstituted and 1,6,7,12-tetrasubstituted perylenetetracarboxy-3,4:9,10-diimide derivatives. <i>New Journal of Chemistry</i> , 2010, 34, 2537.	2.8	56
2	Characterizations of Ohmic and Schottky-behaving contacts of a single ZnO nanowire. <i>Nanotechnology</i> , 2013, 24, 415202.	2.6	27
3	Threshold voltage and turn-on voltage in organic transistors: Sensitivity to contact parasitics. <i>Organic Electronics</i> , 2011, 12, 219-225.	2.6	23
4	High voltage surface potential measurements in ambient conditions: Application to organic thin-film transistor injection and transport characterization. <i>Journal of Applied Physics</i> , 2016, 119, .	2.5	19
5	Tailoring the microstructure and charge transport in conjugated polymers by alkyl side-chain engineering. <i>Journal of Materials Chemistry C</i> , 2016, 4, 286-294.	5.5	19
6	Spin-coated conductive polymer film resistivity measurement using the TLM method. <i>Synthetic Metals</i> , 2006, 156, 838-842.	3.9	18
7	Parametrization of the Gaussian Disorder Model to Account for the High Carrier Mobility in Disordered Organic Transistors. <i>Physical Review Applied</i> , 2021, 15, .	3.8	17
8	Ohmic contact on single ZnO nanowires grown by MOCVD. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2013, 10, 1292-1296.	0.8	15
9	Effective mobility in amorphous organic transistors: Influence of the width of the density of states. <i>Organic Electronics</i> , 2014, 15, 35-39.	2.6	11
10	Generation-recombination in disordered organic semiconductor: Application to the characterization of traps. <i>Organic Electronics</i> , 2021, , 106350.	2.6	3
11	Experimental determination of the lateral resolution of surface electric potential measurements by Kelvin probe force microscopy using biased electrodes separated by a nanoscale gap and application to thin-film transistors. <i>Nanoscale Advances</i> , 2022, 4, 2018-2028.	4.6	2